- 8-Bit Resolution
- Easy Microprocessor interface or Stand-Alone Operation
- Operates Ratiometrically or With 5-V Reference
- Single Channel or Multiplexed Twin Channels With Single-Ended or Differential Input Options
- Input Range 0 to 5 V With Single 5-V Supply
- Inputs and Outputs Are Compatible With TTL and MOS
- Conversion Time of 32 μs at CLK = 250 kHz
- Designed to Be interchangeable With National Semiconductor ADC0831 and ADC0832

DEVICE	TOTAL UNADJUSTED ERROR					
DEVICE	A-SUFFIX	B-SUFFIX				
ADC0831	±1 LSB	± 1/2 LSB				
ADC0832	±1 LSB	± 1/2 LSB				

#### ADC0831 . . . P PACKAGE (TOP VIEW) CSI 8 [] V<sub>CC</sub> IN+∏ 7 CLK 6 DO IN−∏ 3 REF ADC0832...P PACKAGE (TOP VIEW) CS V<sub>CC</sub>/REF CH0 [ 2 7 CLK 6 DO CH1 **∏** 3 GND [ DI 🛚 5

## description

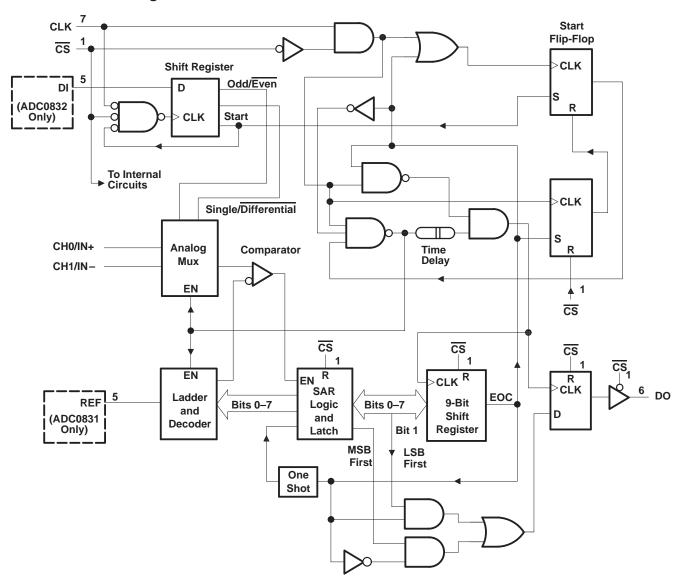
These devices are 8-bit successive-approximation analog-to-digital converters. The ADC0831A and ADC0831B have single input channels; the ADC0832A and ADC0832B have multiplexed twin input channels. The serial output is configured to interface with standard shift registers or microprocessors. Detailed information on interfacing to most popular microprocessors is readily available from the factory.

The ADC0832 multiplexer is software configured for single-ended or differential inputs. The differential analog voltage input allows for common-mode rejection or offset of the analog zero input voltage value. In addition, the voltage reference input can be adjusted to allow encoding any smaller analog voltage span to the full 8 bits of resolution.

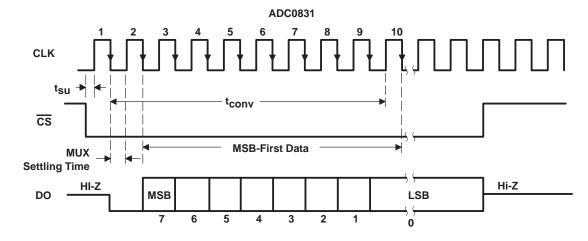
The operation of the ADC0831 and ADC0832 devices is very similar to the more complex ADC0834 and ADC0838 devices. Ratiometric conversion can be attained by setting the REF input equal to the maximum analog input signal value, which gives the highest possible conversion resolution. Typically, REF is set equal to  $V_{CC}$  (done internally on the ADC0832). For more detail on the operation of the ADC0831 and ADC0832 devices, refer to the ADC0834/A DC0838 data sheet.

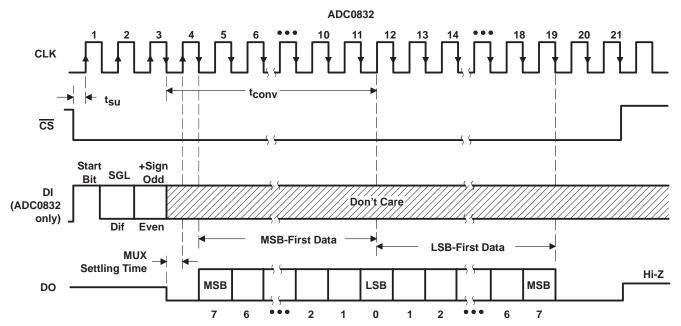
The ADC0831AC, ADC0831BC, ADC0832AC, and ADC0832BC are characterized for operation from 0°C to 70°C. The ADC0831AI, ADC0831BI, ADC0832AI, and ADC0832BI are characterized for operation from -40°C to 85°C.

## functional block diagram



## sequence of operation





#### ADC0832 MUX ADDRESS CONTROL LOGIC TABLE

MUX AI	DDRESS	CHANNE	NUMBER
SGL/DIF	ODD/EVEN	0	1
L	L	+	_
L	Н	_	+
H	L	+	
Н	Н		+

H = high level, L = low level,

- or + = polarity of selected input pin

## ADC0831A, ADC0832A, ADC0831B, ADC0832B A/D PERIPHERALS WITH SERIAL CONTROL

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## absolute maximum ratings over recommended operating free-air temperature range (unless otherwise noted)

Supply voltage, V <sub>CC</sub> (see Note 1)	6.5 V
Input voltage range: Logic	
Analog	$-0.3 \text{ V to V}_{CC} + 0.3$
Input current	±5 mA
Total input current for package	±20 mA
Operating free-air temperature range: C-suffix	0°C to 70°C
I-suffix	40°C to 85°C
Storage temperature range	65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

NOTE 1: All voltage values, except differential voltages, are with respect to the network ground terminal.

### recommended operating conditions

				MIN	NOM	MAX	UNIT
VCC	Supply voltage			4.5	5	6.3	V
VIH	High-level input voltage			2			V
VIL	Low-level input voltage					0.8	V
fclock	Clock frequency					400	kHz
	Clock duty cycle (see Note 2)					60	%
t <sub>wH(C</sub> S)	Pulse duration, CS high						ns
t <sub>su</sub>	Setup time, CS low or ADC0832 data valid before CLK↑						ns
th	Hold time, ADC0832 data valid after CLK↑						ns
т.	Operating free-air temperature	C-suffix		0		70	°C
TA	Operating nee-air temperature	I-suffix		-40		85	C

NOTE 2: The clock duty cycle range ensures proper operation at all clock frequencies. If a clock frequency is used outside the recommended duty cycle range, the minimum pulse duration (high or low) is 1 μs.

# electrical characteristics over recommended range of operating free-air temperature, $V_{CC} = 5 \text{ V}$ , $f_{clock} = 250 \text{ kHz}$ (unless otherwise noted)

### digital section

PARAMETER		TEST COL	UDITIONS+	(	SUFFIX		I	SUFFIX		UNIT
		TEST COI	TEST CONDITIONS†		TYP <sup>‡</sup>	MAX	MIN	TYP <sup>‡</sup>	MAX	UNIT
\/a	High lovel output voltage	$V_{CC} = 4.75 \text{ V},$	$I_{OH} = -360 \mu A$	2.8			2.4			V
VOH	VOH High-level output voltage	$V_{CC} = 4.75 \text{ V},$	$I_{OH} = -10 \mu A$	4.6			4.5			٧
VOL	Low-levl output voltage	$V_{CC} = 4.75 \text{ V},$	I <sub>OL</sub> = 1.6 mA	0.34			0.4			V
lιΗ	High-level input current	V <sub>IH</sub> = 5 V			0.005	1		0.005	1	μΑ
Ι <sub>Ι</sub> L	Low-level input current	V <sub>IL</sub> = 0			-0.005	-1		-0.005	-1	μΑ
loh	High-level output (source) current	VOH = VO,	T <sub>A</sub> = 25°C	-6.5	-14		-6.5	-14		mA
lOL	Low-level output (sink) current	$V_{OL} = V_{CC}$	T <sub>A</sub> = 25°C	8	16		8	16		mA
	High-impedance-state output	V <sub>O</sub> = 5 V,	T <sub>A</sub> = 25°C		0.01	3		0.01	3	^
loz	current (DO)	$V_{O} = 0,$	$T_A = 25^{\circ}C$		-0.01	-3		-0.01	-3	μΑ
Ci	Input capacitance				5			5		pF
Со	Output capacitance				5			5		pF

<sup>†</sup> All parameters are measured under open-loop conditions with zero common-mode input voltage.

<sup>‡</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .



# electrical characteristics over recommended range of operating free-air temperature, $V_{CC} = 5 \text{ V}$ , $f_{clock} = 250 \text{ kHz}$ (unless otherwise noted)

#### analog and converter section

	PARAMETER		TEST CONDITIONS†	MIN	TYP‡	MAX	UNIT
VICR	Common-mode input voltage range		See Note 3	-0.05 to V <sub>CC</sub> +0.05			V
	On-channel	V <sub>I</sub> = 5 V			1		
	I <sub>I(stdby)</sub> Standby input current (see Note 4)	Off-channel	V <sub>I</sub> = 0			-1	
'I(stdby)		On-channel	V <sub>I</sub> = 0			-1	μΑ
		Off-channel	V <sub>I</sub> = 5 V			1	
r <sub>i(REF)</sub>	Input resistance to reference ladder			1.3	2.4	5.9	kΩ

#### total device

	PARAMETER		TEST CONDITIONS <sup>†</sup>	MIN	TYP‡	MAX	UNIT
	Supply ourrent	ADC0831			1	2.5	m ^
Icc	Supply current	ADC0832			3	5.2	mA

<sup>†</sup> All parameters are measured under open-loop conditions with zero common-mode input voltage.

NOTES: 3. If channel IN— is more positive than channel IN+, the digital output code will be 0000 0000. Connected to each analog input are two on-chip diodes that conduct forward current for analog input voltages one diode drop above V<sub>CC</sub>. Care must be taken during testing at low V<sub>CC</sub> levels (4.5 V) because high-level analog input voltage (5 V) can, especially at high temperatures, cause this input diode to conduct and cause errors for analog inputs that are near full-scale. As long as the analog voltage does not exceed the supply voltage by more than 50 mV, the output code will be correct. To achieve an absolute 0 V to 5 V input voltage range requires a minimum V<sub>CC</sub> of 4.95 V for all variations of temperature and load.

4. Standby input currents are currents going into or out of the on or off channels when the A/D converter is not performing conversion and the clock is in a high or low steady-state condition.

# operating characteristics $V_{CC}$ = REF = 5 V, $f_{clock}$ = 250 kHz, $t_r$ = $t_f$ = 20 ns, $T_A$ = 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS§	Al,	AC SUF	FΙΧ	BI,	BC SUFF	ΞIX	UNIT	
	FARAIVETER		LEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
	Supply-voltage variation error		V <sub>CC</sub> = 4.75 V to 5.25 V		±1/16	±1/4		±1/16	±1/4	LSB
I Intal linadilisted error (see Note 5)		$V_{ref} = 5 V$ , $T_A = MIN \text{ to MAX}$			±1			±1/2	LSB	
	Common-mode error		Differential mode		±1/16	±1/4		±1/16	±1/4	LSB
t <sub>m-1</sub>	Propagation delay time, ouput data after CLK↑ (see Note 6)	MSB-first data	C <sub>I</sub> = 100 pF		650	1500		650	1500	ns
<sup>t</sup> pd		LSB-first data	OL = 100 pi		250	600		250	600	110
L	Output disable time,		$C_L = 10 \text{ pF}, R_L = 10 \text{ k}\Omega$		125	250		125	250	20
<sup>t</sup> dis	dis DO after <del>CS</del> ↑		$C_L = 100 \text{ pF}, R_L = 2 \text{ k}\Omega$			500			500	ns
tconv	Conversion time (multiplexer addressing			·		8			8	clock periods

<sup>§</sup> All parameters are measured under open-loop conditions with zero common-mode input voltage. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

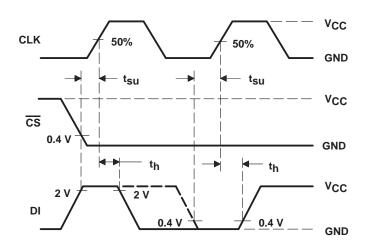
NOTES:5. Total unadjusted error includes offset, full-scale, linearity, and multiplexer errors.



<sup>‡</sup> All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.

<sup>6.</sup> The most significant-bit-first data is output directly from the comparator and therefore requires additional delay to allow for comparator response time. Least-significant-bit-first data applies only to ADC0832.

### PARAMETER MEASUREMENT INFORMATION



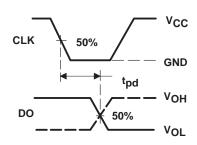
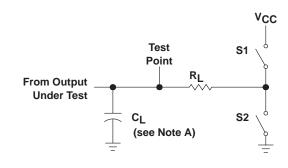
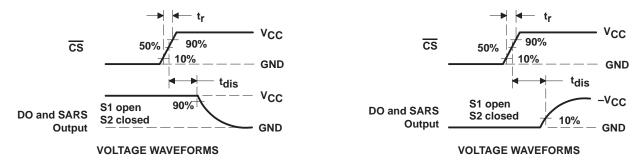


Figure 1. ADC0832 Data Input Timing

Figure 2. Data Output Timing



**LOAD CIRCUIT** 



NOTE A:  $\ensuremath{\text{C}_{L}}$  includes probe and jig capacitance.

Figure 3. Output Disable Time Test Circuit and Voltage Waveforms

#### TYPICAL CHARACTERISTICS

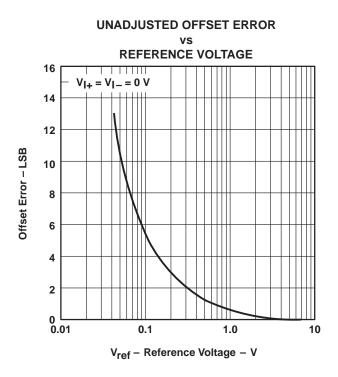
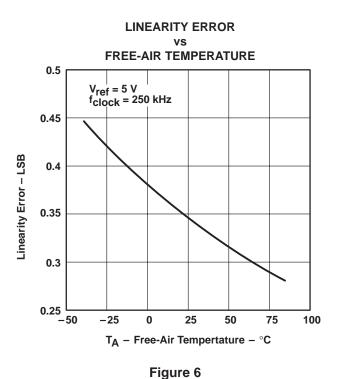


Figure 4



LINEARITY ERROR

VS

REFERENCE VOLTAGE

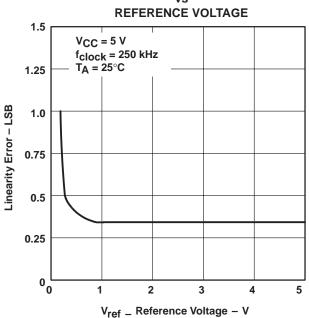


Figure 5

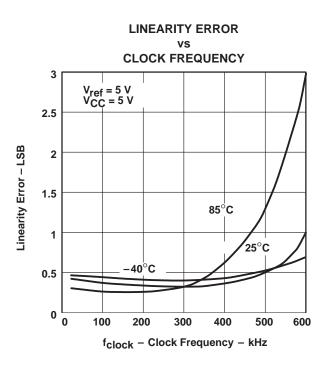
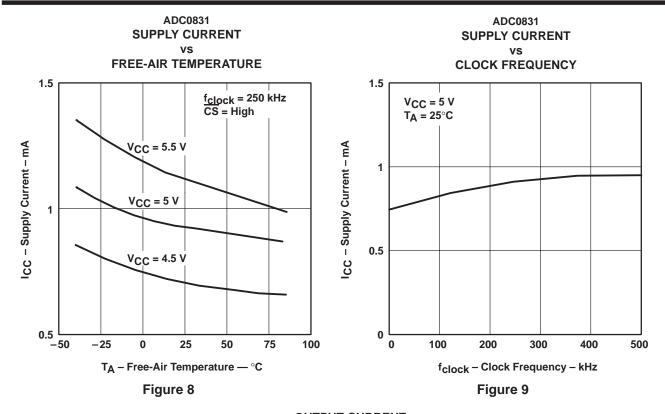
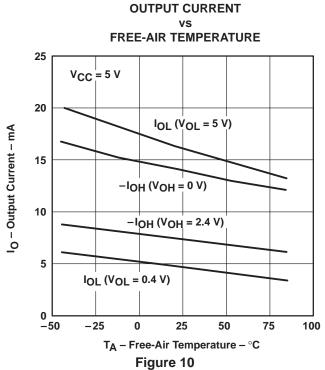


Figure 7





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